

## Certificate of Analysis

### IARM Fe1050-18

Carbon Steel / AISI 1050 / UNS G10500

## Certified Reference Material

Certified Values listed in wt.% with associated uncertainties

<b>Al</b>	<b>0.003 ± 0.002</b>	<b>As</b>	<b>0.0030 ± 0.0009</b>	<b>B</b>	<b>0.0005 ± 0.0003</b>	<b>C</b>	<b>0.499 ± 0.006</b>
<b>Co</b>	<b>0.0056 ± 0.0007</b>	<b>Cr</b>	<b>0.100 ± 0.003</b>	<b>Cu</b>	<b>0.179 ± 0.005</b>	<b>Fe</b>	<b>98.0 ± 0.1</b>
<b>Mn</b>	<b>0.79 ± 0.01</b>	<b>Mo</b>	<b>0.018 ± 0.001</b>	<b>N</b>	<b>0.0097 ± 0.0004</b>	<b>Nb</b>	<b>0.0013 ± 0.0006</b>
<b>Ni</b>	<b>0.068 ± 0.002</b>	<b>O</b>	<b>0.0026 ± 0.0003</b>	<b>P</b>	<b>0.0045 ± 0.0008</b>	<b>S</b>	<b>0.027 ± 0.002</b>
<b>Sb</b>	<b>0.0015 ± 0.0004</b>	<b>Si</b>	<b>0.223 ± 0.006</b>	<b>Sn</b>	<b>0.0103 ± 0.0009</b>	<b>Ti</b>	<b>0.0008 ± 0.0002</b>
<b>V</b>	<b>0.0270 ± 0.0007</b>	<b>Zn</b>	<b>0.003 ± 0.002</b>				

#### Indicative Values listed in ppm

Bi (<50)	Ca (20)	Cd (<10)	H (<1)	Mg (<50)	Pb (1.5)	Se (<50)
Ta (20)	W (5)	Zr (10)				

#### Description and Intended Use

This **Certified Reference Material** is covered under the scope of accreditation to **ISO 17034** by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in **ISO 17025** certified laboratories. This CRM may come in the form of a solid disk, chips, or powder. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

#### Instructions for Use

1. The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface.
2. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams.
3. The material should be stored in a cool, dry location when not in use.
4. Chips are not recommended for gas analysis.

The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Al	As	B	C	Co	Cr	Cu	Fe	Mn	Mo	N	Nb	Ni	O	P	S
1	0.0008	0.0010	0.0002	0.489	0.0040	0.0867	0.160	97.88	0.750	0.0140	0.0090	0.0003	0.0608	0.0020	0.0024	0.0220
2	0.0010	0.0028	0.0003	0.490	0.0041	0.0889	0.170	97.90	0.772	0.0165	0.0092	0.0004	0.0616	0.0021	0.0029	0.0240
3	0.0017	0.0029	0.0003	0.491	0.0041	0.0970	0.173	97.94	0.785	0.0171	0.0092	0.0010	0.0630	0.0023	0.0035	0.0249
4	0.0020	0.0029	0.0005	0.496	0.0050	0.0985	0.174	98.00	0.788	0.0173	0.0093	0.0012	0.0660	0.0025	0.0036	0.0273
5	0.0030	0.0034	0.0005	0.497	0.0050	0.1000	0.175	98.00	0.791	0.0176	0.0093	0.0015	0.0660	0.0028	0.0040	0.0277
6	0.0040	0.0040	0.0010	0.497	0.0052	0.1000	0.176	98.00	0.794	0.0176	0.0100	0.0020	0.0662	0.0030	0.0042	0.0280
7	0.0041	0.0040		0.497	0.0052	0.1007	0.178	98.00	0.794	0.0177	0.0100	0.0020	0.0664	0.0030	0.0044	0.0280
8	0.0067			0.499	0.0058	0.1010	0.179	98.01	0.795	0.0180	0.0101	0.0021	0.0680	0.0030	0.0046	0.0280
9				0.507	0.0060	0.1010	0.180	98.49	0.798	0.0180	0.0102		0.0690		0.0050	0.0280
10				0.515	0.0060	0.1014	0.180		0.800	0.0183	0.0105		0.0690		0.0050	0.0280
11				0.516	0.0062	0.1014	0.181		0.801	0.0184			0.0706		0.0057	0.0300
12					0.0066	0.1030	0.181		0.803	0.0190			0.0710		0.0060	0.0319
13					0.0070	0.1060	0.183		0.809	0.0209			0.0714		0.0072	
14					0.0086	0.1060	0.196		0.812	0.0210			0.0730			
15						0.1060	0.198		0.831				0.0748			
Mean	0.0029	0.0030	0.0005	0.499	0.0056	0.0998	0.179	98.02	0.795	0.0180	0.0097	0.0013	0.0678	0.0026	0.0045	0.0273
STDV.	0.0020	0.0010	0.0003	0.009	0.0013	0.0056	0.009	0.18	0.018	0.0017	0.0005	0.0007	0.0041	0.0004	0.0013	0.0026
<b>Certified</b>	<b>0.003</b>	<b>0.0030</b>	<b>0.0005</b>	<b>0.499</b>	<b>0.0056</b>	<b>0.100</b>	<b>0.179</b>	<b>98.0</b>	<b>0.79</b>	<b>0.018</b>	<b>0.0097</b>	<b>0.0013</b>	<b>0.068</b>	<b>0.0026</b>	<b>0.0045</b>	<b>0.027</b>
U <sub>CRM</sub>	0.002	0.0009	0.0003	0.006	0.0007	0.003	0.005	0.1	0.01	0.001	0.0004	0.0006	0.002	0.0003	0.0008	0.002
Methods	I,IM,O	IM,I,O	I,IM,O	C,O	I,IM,O	I,IM,O,X	I,IM,O,X	I,O,X	I,O,X	I,IM,O,X	F	I,IM,O	I,IM,O,X	F	I,IM,O,X	C,O

	Sb	Si	Sn	Ti	V	Zn	Bi	Ca	Cd	H	Mg	Pb	Se	Ta	W	Zr
1	0.0010	0.208	0.0070	0.0003	0.0250	0.0006	0.0030	0.0007	<0.001	0.0001	0.0021	0.0001	<0.001	0.0008	0.0003	0.0001
2	0.0011	0.209	0.0085	0.0005	0.0259	0.0007	<0.001	0.0012	<0.001	0.0002	<0.001	0.0001	<0.005	0.0010	0.0004	0.0008
3	0.0012	0.218	0.0090	0.0008	0.0260	0.0020		0.0012		<0.0001	<0.001	0.0002		0.0011	0.0005	0.0009
4	0.0017	0.218	0.0100	0.0008	0.0260	0.0024		0.0019				0.0002		0.0022	0.0005	0.0009
5	0.0017	0.219	0.0100	0.0010	0.0268	0.0030		0.0070				0.0002		0.0030	0.0010	0.0031
6	0.0019	0.220	0.0103	0.0010	0.0269	0.0031		<0.005				<0.001		<0.0005	<0.001	<0.001
7	0.0020	0.220	0.0108	0.0010	0.0269	0.0042		<0.005				<0.001		<0.001	<0.001	<0.001
8		0.223	0.0110		0.0270	0.0062						<0.001		<0.001	<0.005	<0.002
9		0.224	0.0110		0.0271							<0.002		<0.005	<0.005	<0.005
10		0.225	0.0112		0.0272							<0.005		<0.005	<0.01	<0.005
11		0.230	0.0113		0.0273							<0.005				
12		0.231	0.0117		0.0290											
13		0.234	0.0126		0.0294											
14		0.248														
15																
Mean	0.0015	0.223	0.0103	0.0008	0.0270	0.0028		0.0024		0.0001	0.0021	0.0001		0.0016	0.0005	0.0012
STDV.	0.0004	0.010	0.0015	0.0003	0.0012	0.0018		0.0026		0.0001		0.0001		0.0009	0.0003	0.0011
<b>Certified</b>	<b>0.0015</b>	<b>0.223</b>	<b>0.0103</b>	<b>0.0008</b>	<b>0.0270</b>	<b>0.003</b>	<b>(&lt;0.005)</b>	<b>(0.002)</b>	<b>(&lt;0.001)</b>	<b>(&lt;0.0001)</b>	<b>(&lt;0.005)</b>	<b>(0.00015)</b>	<b>(&lt;0.005)</b>	<b>(0.002)</b>	<b>(0.0005)</b>	<b>(0.001)</b>
U <sub>CRM</sub>	0.0004	0.006	0.0009	0.0002	0.0007	0.002										
Methods	IM,I	I,IM,O,X	IM,I,O,X	I,IM,O	I,IM,O,X	I,IM	IM	I,IM	IM	F	IM	IM,I,O	IM	I,IM	I,IM,O	I,IM,O

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

### Certification Laboratories

Laboratory Testing, Inc.	Hatfield, PA	NSL Analytical Services	Cleveland, OH
IMR Test Labs	Lansing, NY	Dirats Laboratories	Westfield, MA
Applied Technical Services	Marietta, GA	EAG Laboratories	Liverpool, NY
LGC Standards	Manchester, NH	Luvak Laboratories Inc.	Boylston, MA
Massachusetts Materials Research Inc.	West Boylston, MA	Connecticut Metallurgical Inc	East Hartford, CT
SGS MSi	Melrose Park, IL		

Certification laboratories have demonstrated performance and traceability by utilizing a variety of test methods under the scope of ISO 17025 or have demonstrated equivalent performance. Some of the specific CRMs and SRMs used in the analysis of the material covered by this certificate are:

NIST 3168a NIST 361 NIST 139B NIST 184 NIST 37E

### Homogeneity and Uncertainty

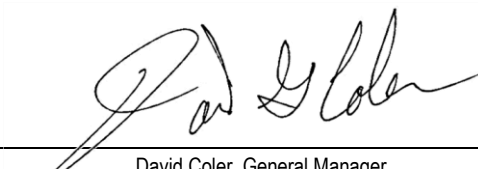
"Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where  $N_{prod}$  is the number of units produced and  $N_{min}$  is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculate uncertainty due to inhomogeneity ( $U_{hom}$ ). Uncertainty of the material is calculated by equation 2, where  $H=U_{hom}$ ,  $S$  = Standard deviation,  $t$  = t-value at 95% CI, and  $n$  = number of observations.

$$1. N_{min} = \max(10, \sqrt[3]{N_{prod}})$$

$$2. U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

### Expiration

The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

  
 David Coler, General Manager  
 Analytical Reference Materials International

